


<b>Search Notes</b>  	<b>Application/Control No.</b>  10082794	<b>Applicant(s)/Patent Under Reexamination</b>  BAU ET AL.
	<b>Examiner</b>  Rutten, J. Derek	<b>Art Unit</b>  2192

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	2/8/07	/jdr/

INTERFERENCE SEARCH			
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